

P-Channel 150-V (D-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
- 150	0.75 at V _{GS} = - 10 V	- 1.4	8 nC
	0.79 at V _{GS} = - 6 V	- 1.3	

FEATURES

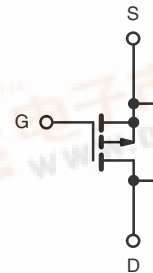
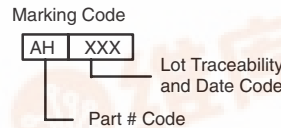
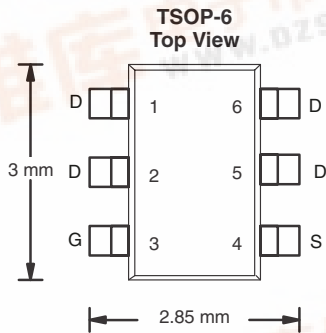
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC



RoHS
 COMPLIANT
 HALOGEN
FREE
 Available

APPLICATIONS

- Active Clamp Circuits in DC/DC Power Supplies



Ordering Information: Si3437DV-T1-E3 (Lead (Pb)-free)
 Si3437DV-T1-GE3 (Lead (Pb)-free and Halogen-free)

P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted					
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 150	V		
Gate-Source Voltage	V _{GS}	± 20			
Continuous Drain Current (T _J = 150 °C)	I _D	T _C = 25 °C	- 1.4	A	
		T _C = 70 °C	- 1.1		
		T _A = 25 °C	- 1.1 ^{b,c}		
		T _A = 70 °C	- 0.88 ^{b,c}		
Pulsed Drain Current	I _{DM}	- 5			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	- 2.6		
		T _A = 25 °C	1.6 ^{b,c}		
Avalanche Current	I _{AS}	5			
Single-Pulse Avalanche Energy	E _{AS}	1.25	mJ		
Maximum Power Dissipation	P _D	T _C = 25 °C	3.2	W	
		T _C = 70 °C	2.1		
		T _A = 25 °C	2 ^{b,c}		
		T _A = 70 °C	1.25 ^{b,c}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	R _{thJA}	51	62.5	°C/W	
Maximum Junction-to-Foot	R _{thJF}	32	39		

Notes:

- T_C = 25 °C.
- Surface Mounted on 1" x 1" FR4 board.
- t = 5 s.
- Maximum under Steady State conditions is 110 °C/W.



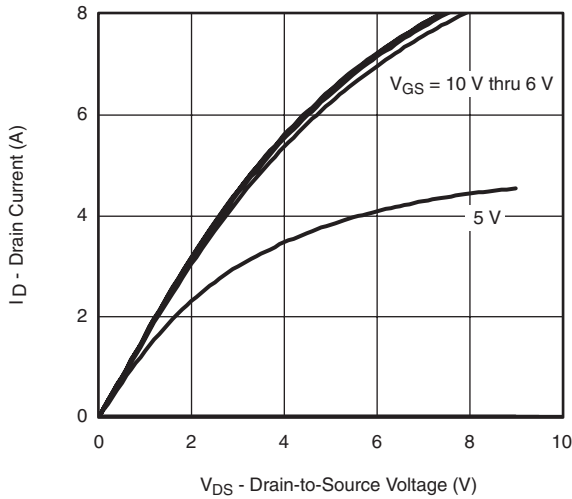
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$	-150			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250\ \mu\text{A}$		-160		mV/ $^\circ\text{C}$
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		5.5			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$	-2		-4	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -150\text{ V}, V_{GS} = 0\text{ V}$			-1	μA
		$V_{DS} = -150\text{ V}, V_{GS} = 0\text{ V}, T_J = 55^\circ\text{C}$			-10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \geq -10\text{ V}, V_{GS} = -10\text{ V}$	-3			A
Drain-Source On-State Resistance ^a	$R_{DS(on)}$	$V_{GS} = -10\text{ V}, I_D = -1.4\text{ A}$		0.61	0.75	Ω
		$V_{GS} = -6\text{ V}, I_D = -1\text{ A}$		0.64	0.79	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -10\text{ V}, I_D = -1.4\text{ A}$		4.5		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -50\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		510		pF
Output Capacitance	C_{oss}		30			
Reverse Transfer Capacitance	C_{rss}		21			
Total Gate Charge	Q_g	$V_{DS} = -75\text{ V}, V_{GS} = -10\text{ V}, I_D = -1\text{ A}$		12.2	19	nC
				8	12	
Gate-Source Charge	Q_{gs}	$V_{DS} = -75\text{ V}, V_{GS} = -6\text{ V}, I_D = -1\text{ A}$		2.1		
Gate-Drain Charge	Q_{gd}		3.9			
Gate Resistance	R_g	$f = 1\text{ MHz}$		8.5	13	Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -75\text{ V}, R_L = 75\ \Omega$ $I_D \cong -1\text{ A}, V_{GEN} = -10\text{ V}, R_g = 1\ \Omega$		9	15	ns
Rise Time	t_r		11	18		
Turn-Off Delay Time	$t_{d(off)}$		28	42		
Fall Time	t_f		12	18		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -75\text{ V}, R_L = 75\ \Omega$ $I_D \cong -1\text{ A}, V_{GEN} = -6\text{ V}, R_g = 1\ \Omega$		14	21	
Rise Time	t_r		29	44		
Turn-Off Delay Time	$t_{d(off)}$		23	35		
Fall Time	t_f		14	21		
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			-1.4	A
Pulse Diode Forward Current	I_{SM}				-5	
Body Diode Voltage	V_{SD}	$I_S = -1\text{ A}, V_{GS} = 0\text{ V}$		-0.8	-1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -1.2\text{ A}, dI/dt = 100\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		60	90	ns
Body Diode Reverse Recovery Charge	Q_{rr}		120	180	nC	
Reverse Recovery Fall Time	t_a		35		ns	
Reverse Recovery Rise Time	t_b		25			

Notes:

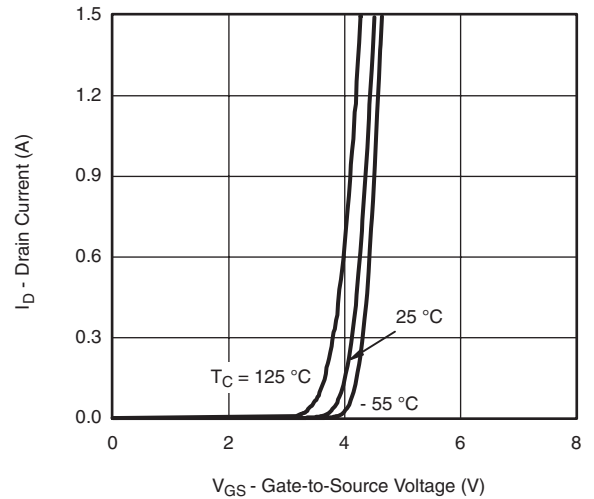
- a. Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

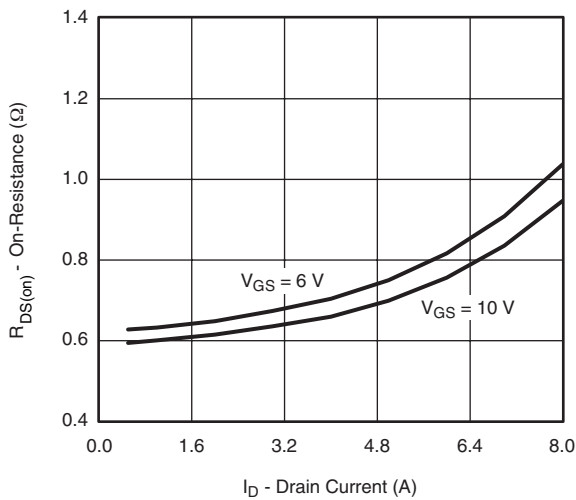
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



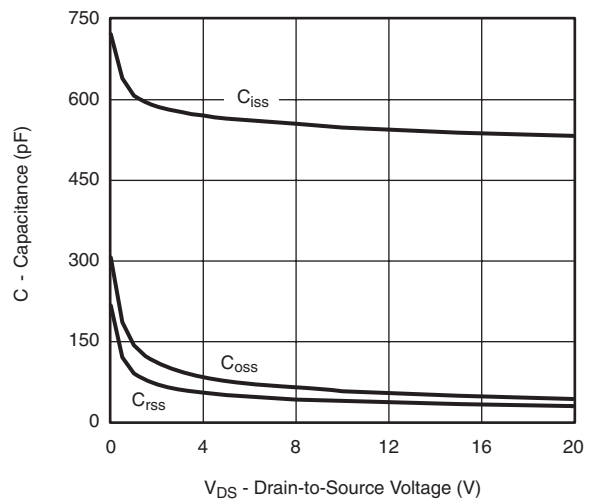
Output Characteristics



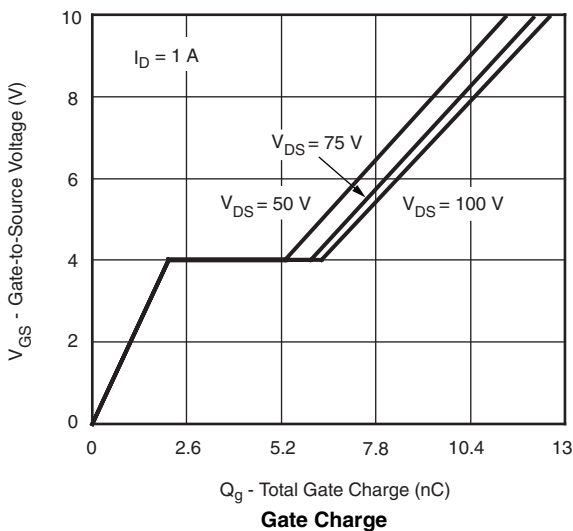
Transfer Characteristics



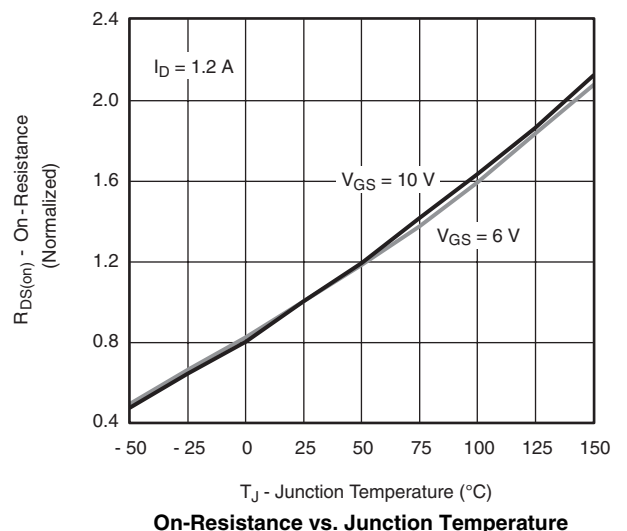
On-Resistance vs. Drain Current and Gate Voltage



Capacitance

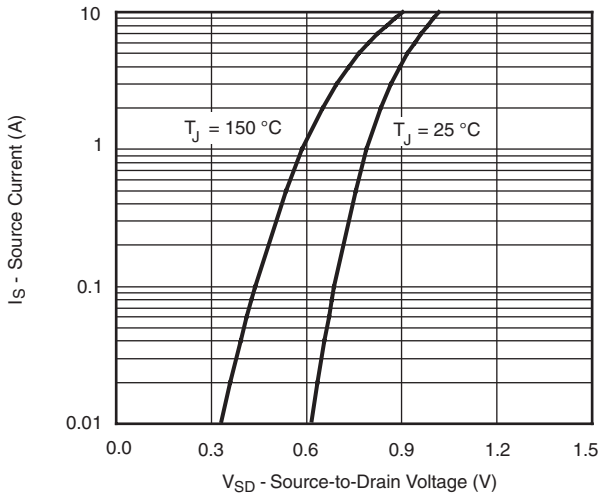


Gate Charge

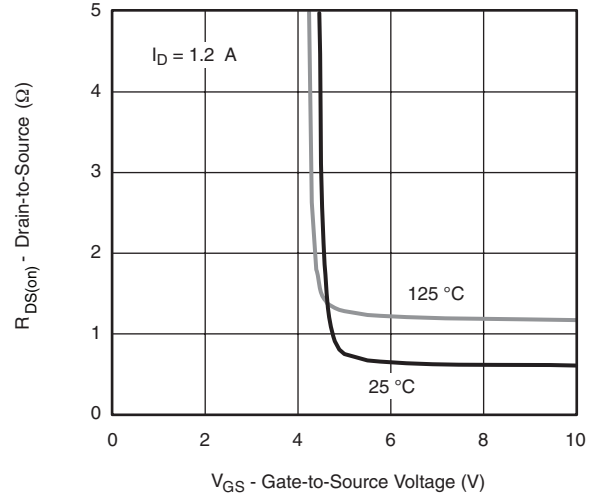


On-Resistance vs. Junction Temperature

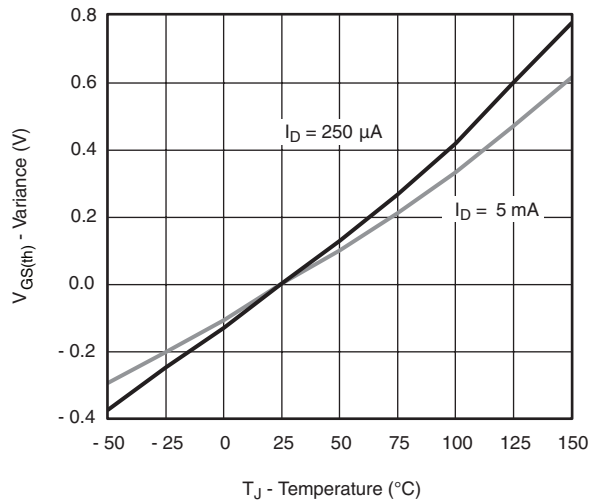
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



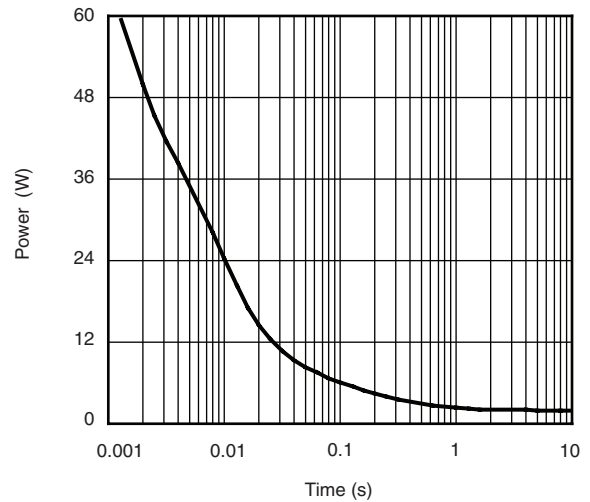
Source-Drain Diode Forward Voltage



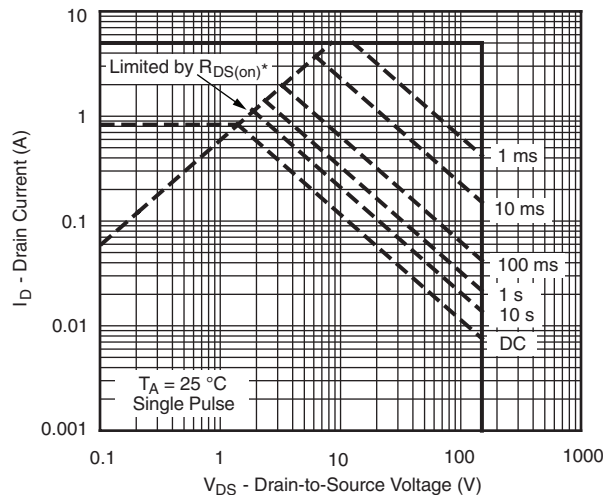
On-Resistance vs. Gate-to-Source Temperature



Threshold Voltage



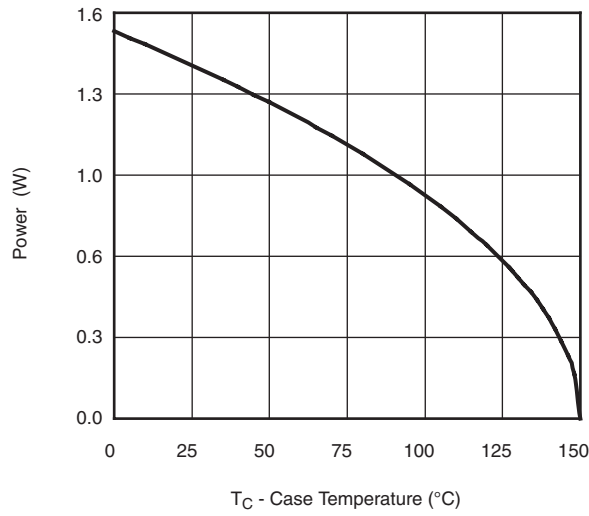
Single Pulse Power, Junction-to-Ambient



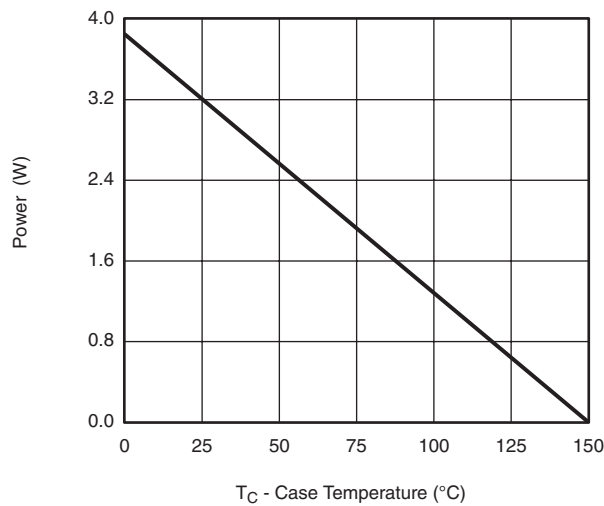
* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

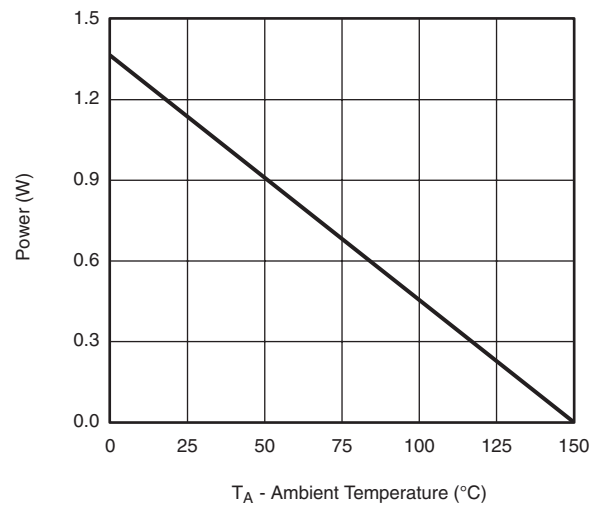
MOSFET TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Current Derating*



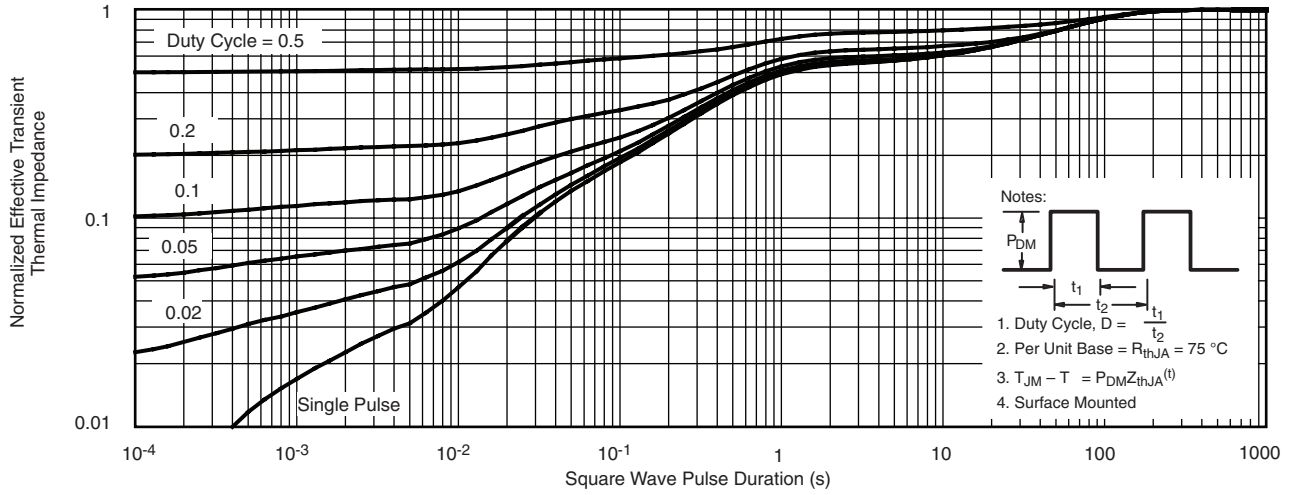
Power, Junction-to-Foot



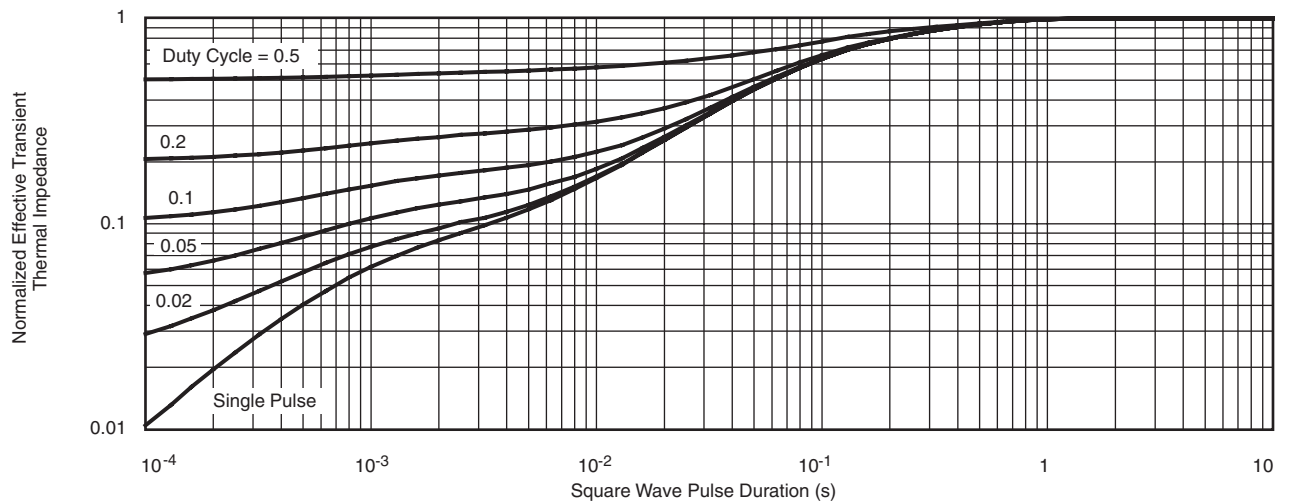
Power Derating, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max)} = 150\text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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